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Substitute Form PTO-1449 (Modified)	U.S. Department of Commerce Patent and Trademark Office	Attorney Docket No. 20228-0013US1	Application No. 10/580,698	
Information Disclosure Statement by Applicant (Use several sheets if necessary)		Applicant Damian Fiolka et al.		
		Filing Date November 29, 2006	Group Art Unit 2872	

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